

## 2-line IPAD™, ultra low capacitance protection for high speed USB

### Features

- Ultra low diode capacitance (1.2 pF max)
- Two data lines (D+ and D-) protected against 15 kV ESD
- Breakdown voltage  $V_{BR} = 6.0 \text{ V min}$
- Flip Chip 400  $\mu\text{m}$  pitch, lead-free
- Very low leakage current
- Very small PCB area
- RoHS compliant

### Benefits

- Minimized impact on rise and fall times for maximum data integrity
- Low PCB space occupation
- Higher reliability offered by monolithic integration

### Complies with the following standards

- IEC 61000-4-2 level 4 on external pins:
  - 15 kV (air discharge)
  - 8 kV (contact discharge)
- MIL STD 883G - Method 3015.7
  - 25 kV (Human body model)

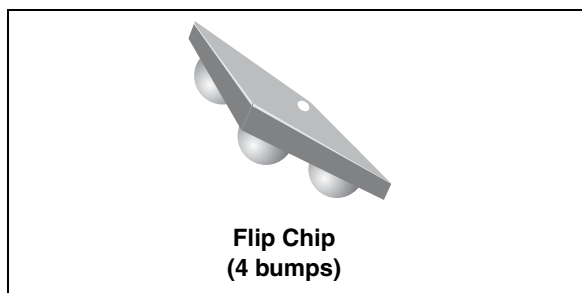
### Application

- High speed USB port in wireless handsets (up to 480 Mb/s according to USB 2.0 high speed specification)

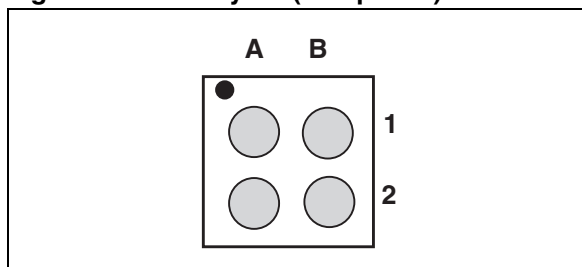
### Description

The USBULC6-2F3 is a monolithic, application specific discrete device dedicated to ESD protection of high speed interfaces.

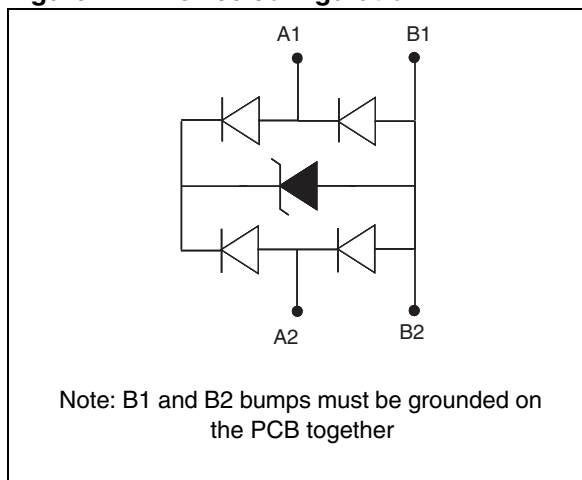
Its ultra low line capacitance secures a high level of signal integrity without compromising the protection of downstream sensitive chips against the most stringently characterized ESD strikes.



**Figure 1. Pin layout (bump side)**



**Figure 2. Device configuration**



**TM:** IPAD is a trademark of STMicroelectronics.

# 1 Characteristics

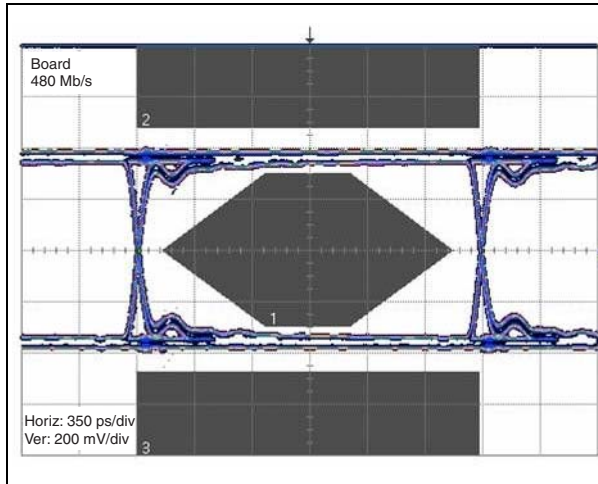
**Table 1. Absolute maximum ratings ( $T_{amb} = 25\text{ °C}$ )**

Symbol	Parameter	Value	Unit
$V_{PP}$	ESD discharge IEC 61000-4-2, air discharge ESD discharge IEC 61000-4-2, contact discharge	15 8	kV
$P_{PP}$	Peak pulse power dissipation (8/20 $\mu$ s)	60	W
$T_j$	Maximum junction temperature	125	$^{\circ}\text{C}$
$T_{op}$	Operating temperature range	-30 to + 85	$^{\circ}\text{C}$
$T_{stg}$	Storage temperature range	-55 to +150	$^{\circ}\text{C}$

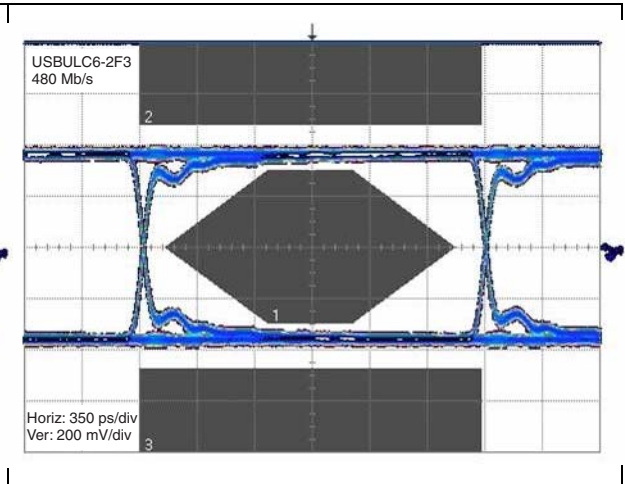
**Table 2. Electrical characteristics ( $T_{amb} = 25\text{ °C}$ )**

Symbol	Parameter				
$V_{BR}$	Breakdown voltage				
$I_{RM}$	Leakage current @ $V_{RM}$				
$V_{RM}$	Stand-off voltage				
$V_{CL}$	Clamping voltage				
$R_d$	Dynamic impedance				
$I_{PP}$	Peak pulse current				
$\alpha T$	Voltage temperature coefficient				
$V_F$	Forward voltage drop				
$V_F$	Forward voltage drop				
Symbol	Test conditions	Min.	Typ.	Max.	Unit
$V_{BR}$	$I_R = 1\text{ mA}$	6		9	V
$I_{RM}$	$V_{RM} = 3\text{ V}$			100	nA
$R_d$	Exponential wave form 8/20 $\mu$ s, $I_{pp} = 1\text{ to }5\text{ A}$		1.6		$\Omega$
$\alpha T$	$I_R = 1\text{ mA}$			5	$10^{-4}/^{\circ}\text{C}$
$C_{line}$	$V_{LINE} = 0\text{ V}$ , $V_{OSC} = 30\text{ mV}$ , $F = 1\text{ MHz}$			1.2	pF

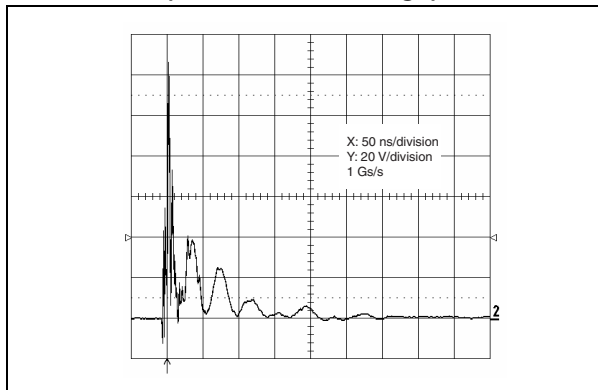
**Figure 3. Eye diagram, board only (according to USB high speed specification)**



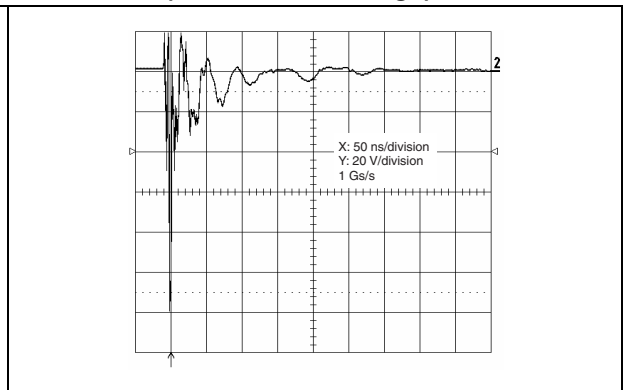
**Figure 4. Eye diagram, board with USBULC6-2F3 (according to USB 2.0 high speed specification)**



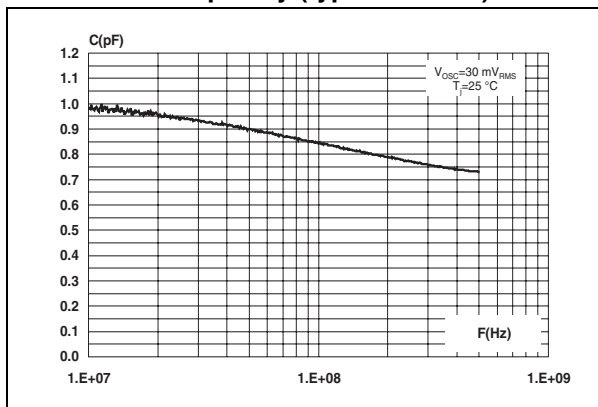
**Figure 5. ESD response to IEC 61000-4-2 (+15 kV air discharge)**



**Figure 6. ESD response to IEC 61000-4-2 (-15 kV air discharge)**



**Figure 7. Junction capacitance versus frequency (typical values)**



**Figure 8. Analog crosstalk measurement**

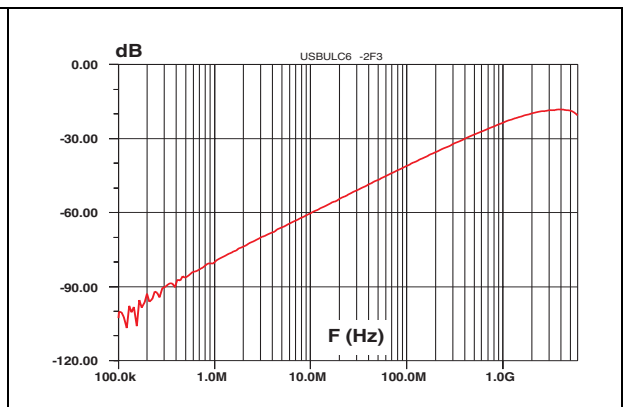


Figure 9. S21 (dB) attenuation measurement

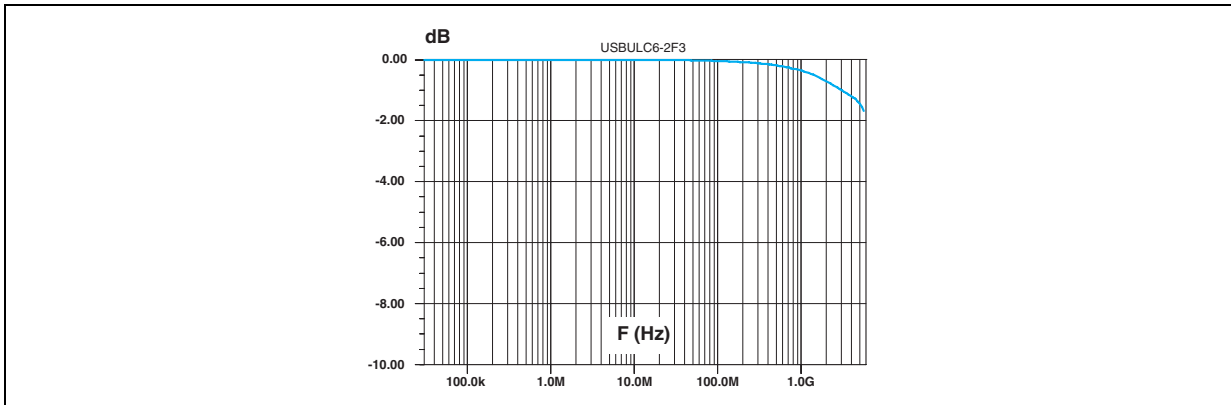


Figure 10. Digital crosstalk

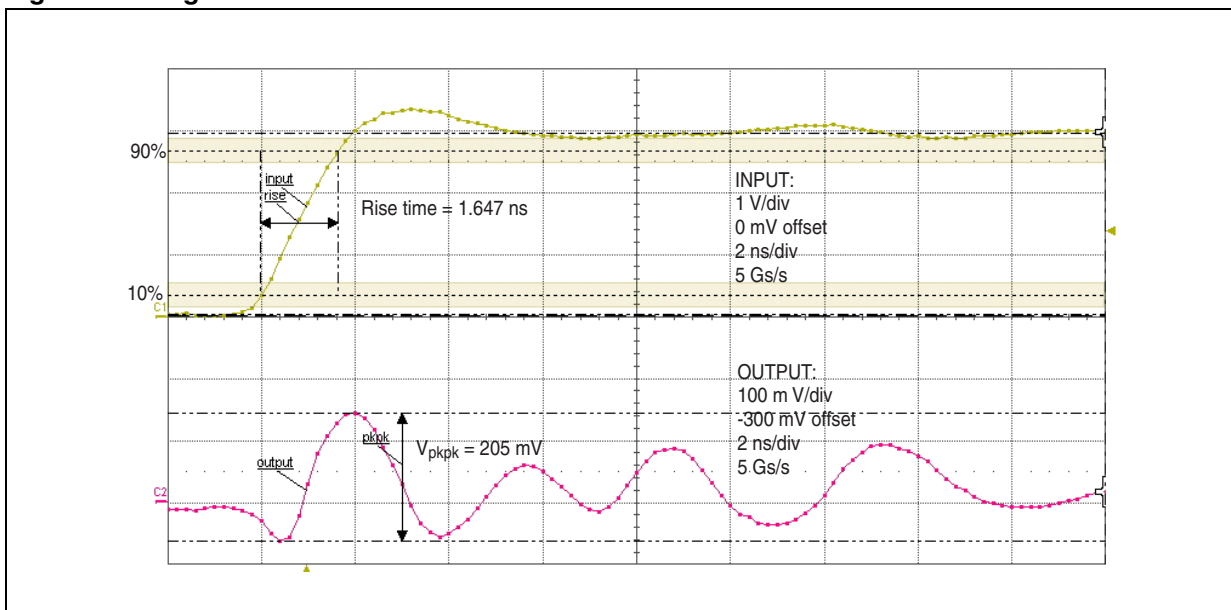


Figure 11. Relative variation of peak pulse power versus initial junction temperature

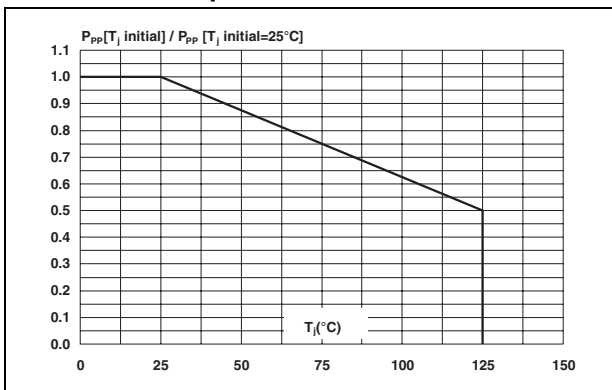


Figure 12. Peak pulse power versus exponential pulse duration

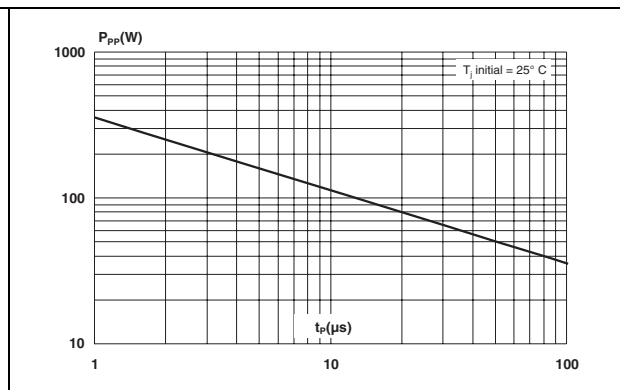


Figure 13. Clamping voltage versus peak pulse current (typical values, exponential waveform)

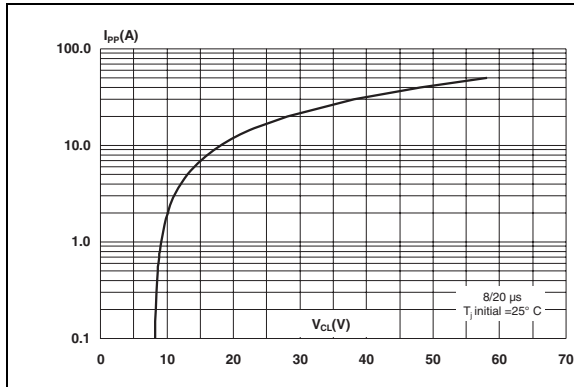
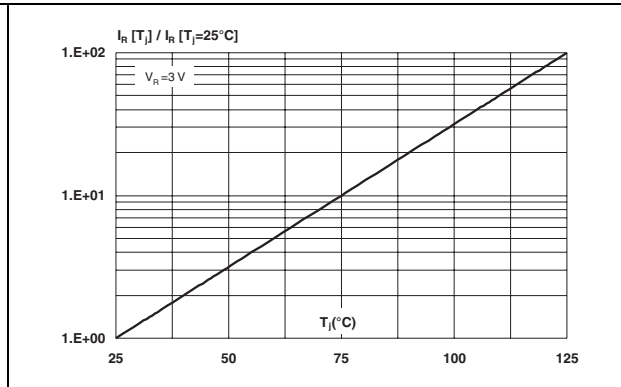
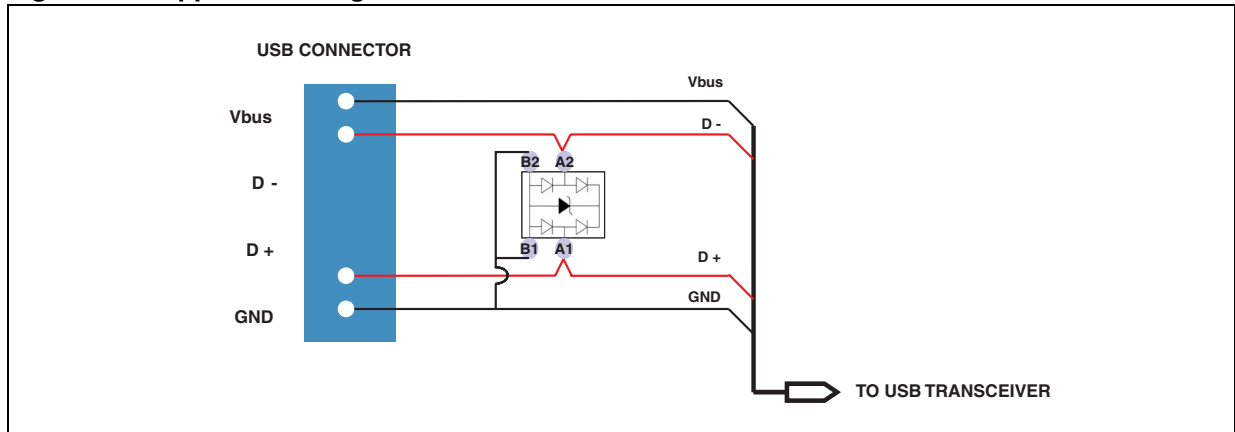


Figure 14. Relative variation of leakage current versus junction temperature (typical values)



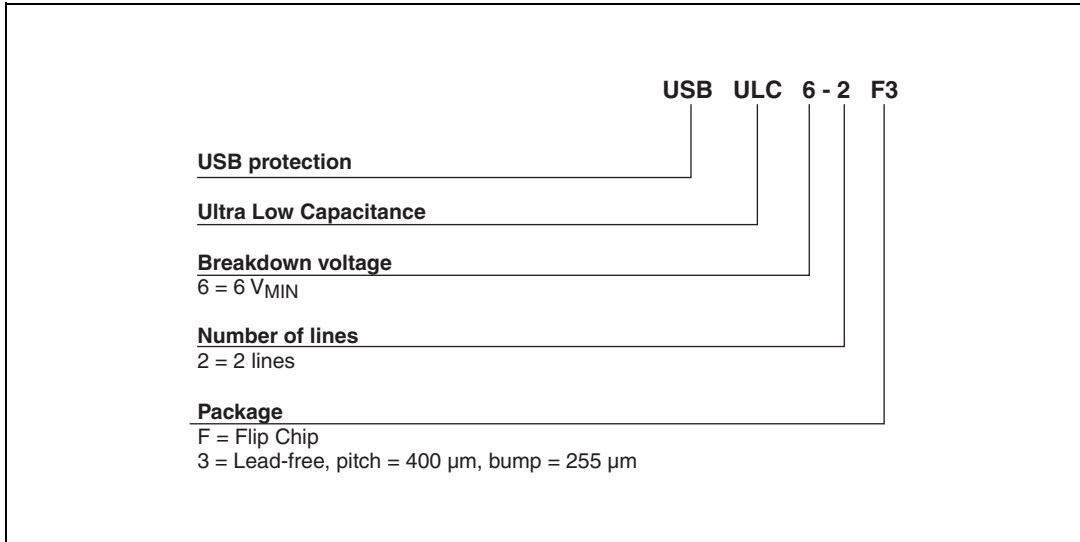
## 2 Application information

Figure 15. Application diagram



### 3 Ordering information scheme

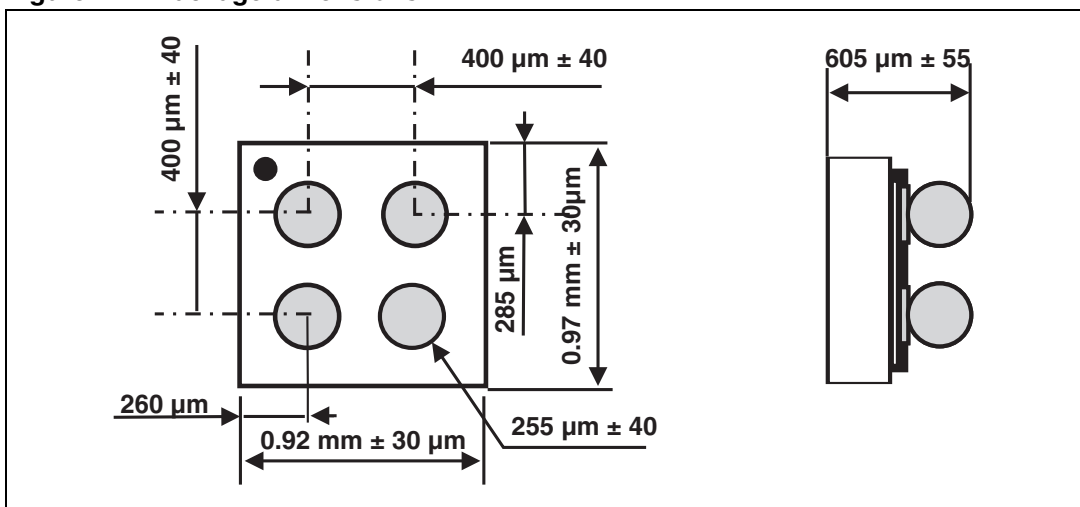
Figure 16. Ordering information scheme



### 4 Package information

In order to meet environmental requirements, ST offers these devices in ECOPACK<sup>®</sup> packages. These packages have a lead-free second level interconnect. The category of second level interconnect is marked on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at [www.st.com](http://www.st.com).

Figure 17. Package dimensions





## 6 Revision history

Table 4. Document revision history

Date	Revision	Changes
15-Dec-2006	1	Initial release.
29-Apr-2008	2	Updated ECOPACK statement. Updated <a href="#">Figure 17</a> , <a href="#">Figure 18</a> and <a href="#">Figure 20</a> . Reformatted to current standards.



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